

FIG. 1

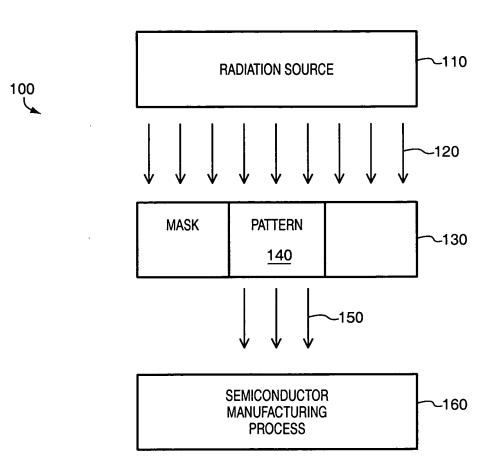
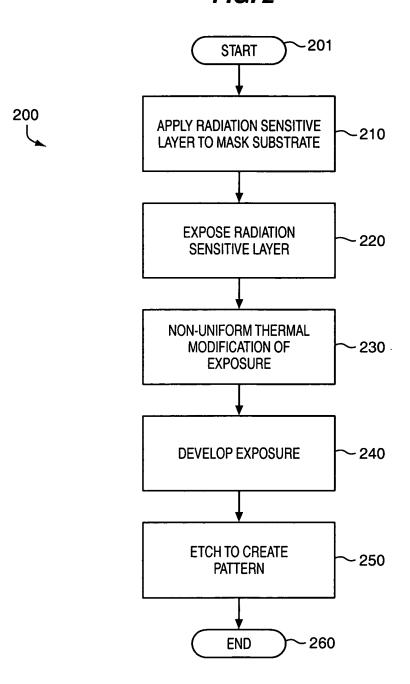




FIG. 2





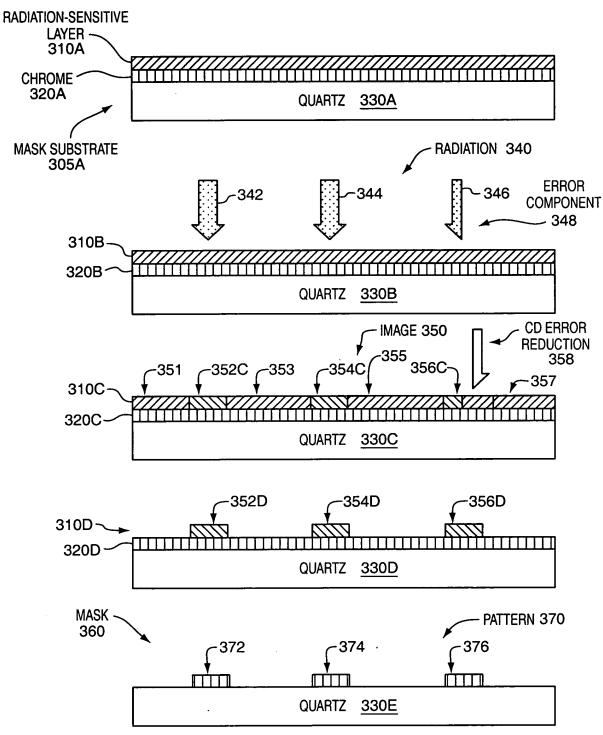


FIG. 3



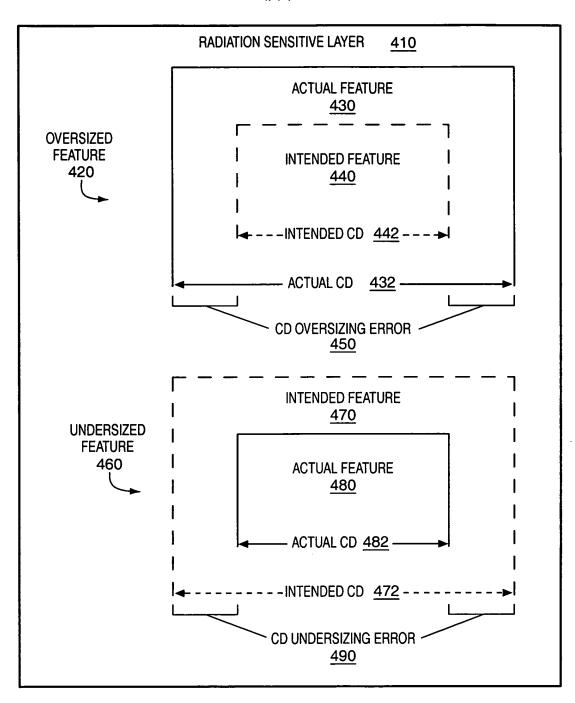


FIG. 4



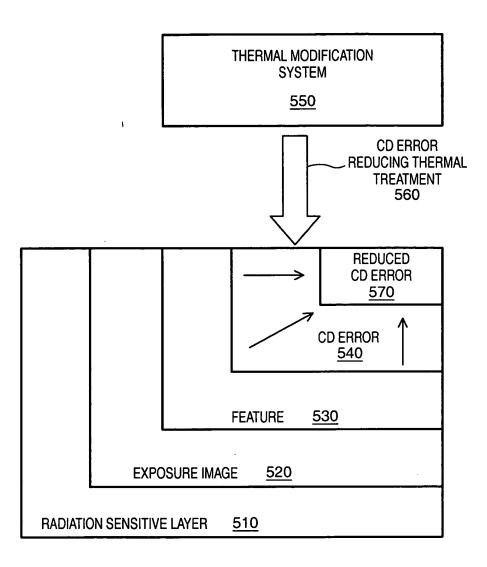


FIG. 5



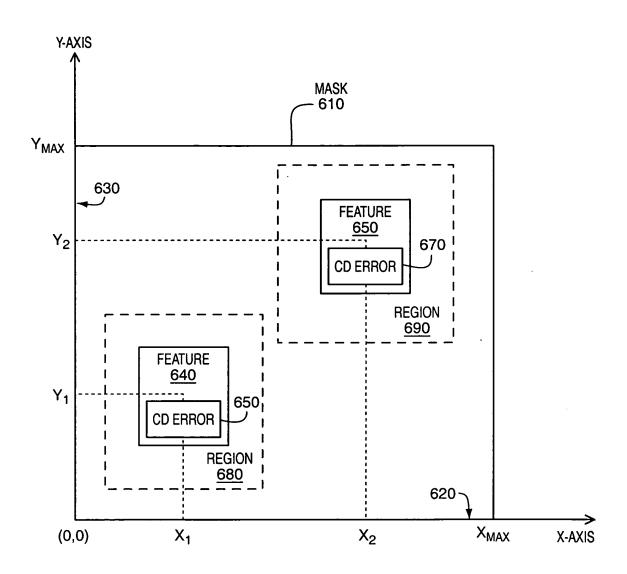
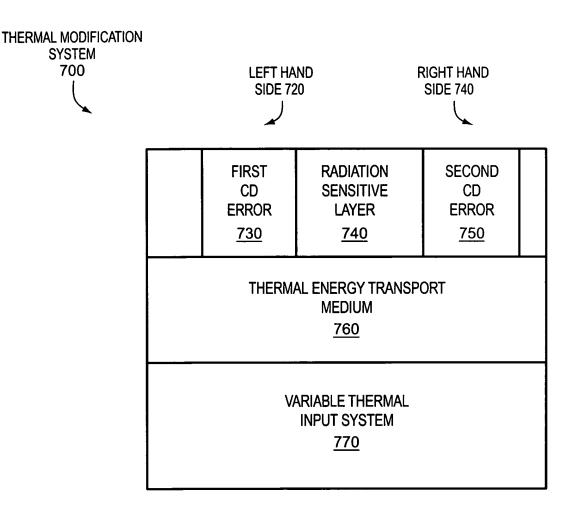


FIG. 6

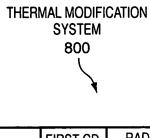


SYSTEM 700

Title: "Post Exposure Modification of Critical Dimensions In Mask Fabrication" Inventors: Takeshi et al. Application No.: 09/965,280 Attorney Docket No.: 42P11370 Blakely, Sokoloff, Taylor & Zafman 303-740-1980







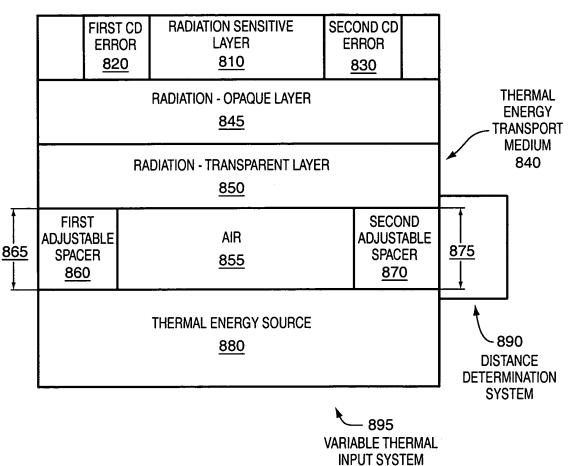
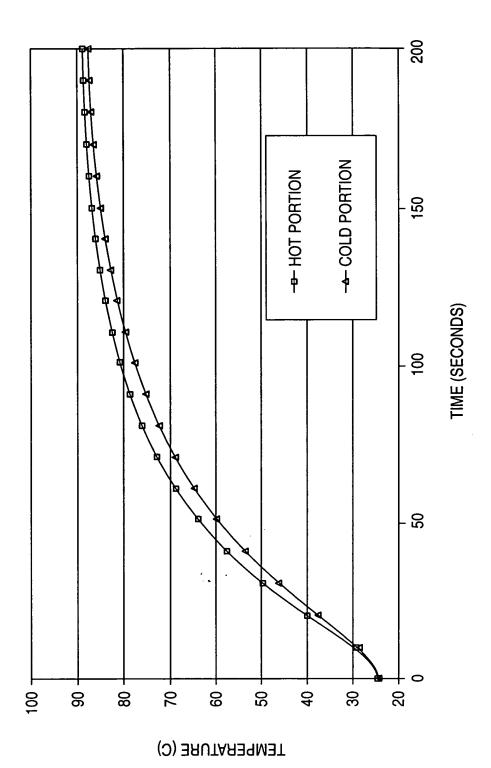


FIG. 8





F/G. 9



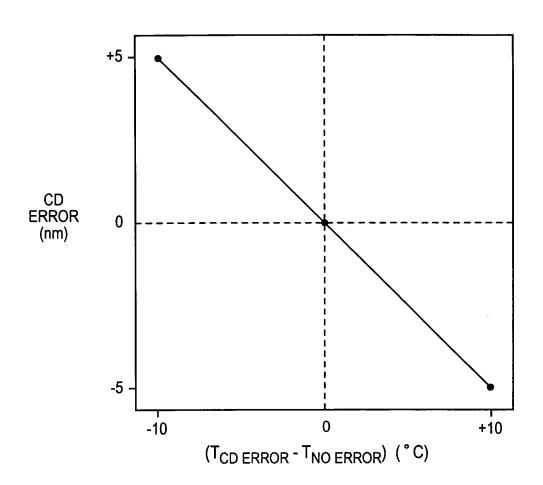


FIG. 10



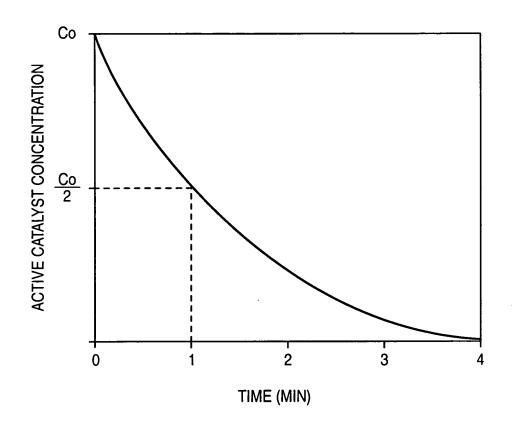


FIG. 11



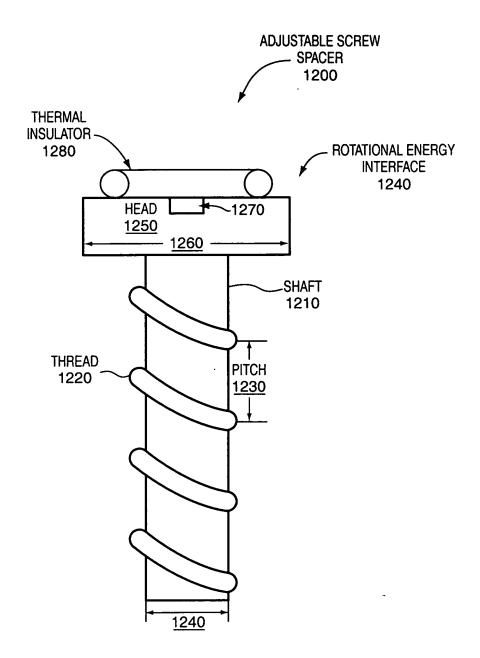


FIG. 12



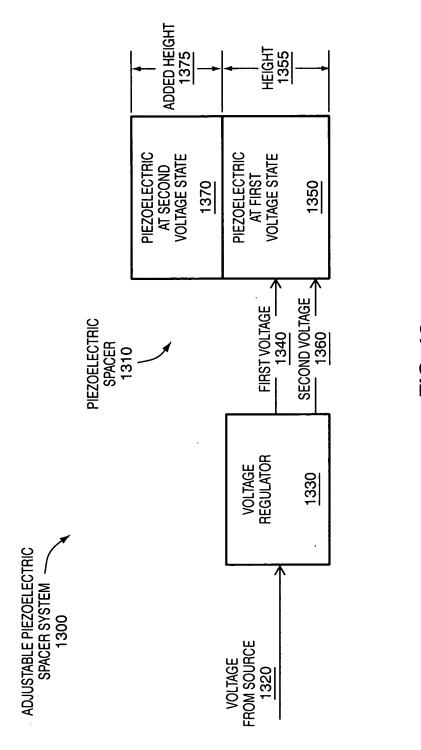


FIG. 13



